Re-entrant antiferromagnetism in the exchange-coupled IrMn/NiFe system

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101° Congresso Nazionale SIF, Roma 21-25 Settembre 2015

Objective

Description of the dynamic magnetic behavior of the antiferromagnet in exchange-coupled FM/ AFM **NiFe/IrMn bilayers**

Re-entrant antiferromagnetism

• From the continuous NiFe/IrMn film to **dot arrays**: spatial confinement and exchange coupling mechanism



NiFe/IrMn film

Si / Cu[5 nm] / Py[5 nm] / IrMn[6 nm] / Cu [5 nm]

Py: Ni₈₀Fe₂₀ **IrMn**: Ir₂₅Mn₇₅

Reference film: Si / Cu[5 nm] / Py[5 nm] / Cu [5 nm]

Deposition by dc-magnetron sputtering

Ar atmosphere, deposition rate \cong 0.2 nm/s

H_{dep} = 400 Oe

Hysteresis loops (5-400 K temperature range)



step 1: FC@ $H_{cool} = 500 \text{ Oe}$ Magnetization reversal study -SQUID measurement 400 K 5 K procedure step 2: M vs T @ H_{inv} H 1.0 1.0 0.9 0.5 0.5 M/M H_{right} H_{left} M/Ms 0.0 0.0 T = 5 K-0.5 H_{inv} = - 50 Oe -0.5 – H_{inv} = -100 Oe ■ H_{inv} = -200 Oe -1.0 -1.0 100 200 300 400 0 -0.5 -1.0 0.0 H (kOe) T (K)





AFM film consists of noninteracting nanograins U
Distribution of effective
anisotropy energy barriers ∆E



We obtain information on the anisotropy energy barrier distribution of the AFM as it is felt by the FM component

F. Spizzo et al., J. Phys.: Condens. Matter 25, 386001 (2013)





Existence of a disordered AFM region at the interface with the NiFe phase

TEM results confirm our prediction on the structure of the AFM phase

T > 100 K

Only the interfacial AFM spins tightly anchored to the spin lattice of the bulk AFM nanograins contribute to $\rm H_{\rm ex}$

T ~ 100 K

The frozen collective state breaks up. Polarizing action of bulk AFM spins on the interfacial ones prevents the development of a paramagnetic state.

Re-entrant antiferromagnetism

T< 100 K

AFM interfacial spins are frozen and subjected to a high effective anisotropy.

H_{ex} decreses and finally the EB effect disappears

H_{ex} is maximized

From the continuous film to dot arrays

Si / Cu[5 nm] / IrMn[10 nm] / Py [5 nm]











At low temperature

The correlation length among the AFM interfacial spins increases with reducing T



Object Oriented MicroMagnetic Framework





Dependence of H_{ex} on the AFM correlation length λ

Dot size = 1200 nm

OOMMF cell size = 10 nm

 $K_{AFM} = 2 \times 10^7 \text{ erg/cm}^3 \text{ cells}$:

FM/AFM exchange interaction = 10^{-7} erg/cm

Different cell size: 10, 20, 100, 200, 300 nm

F. Spizzo et al., Phys. Rev. B 91 (2015) 064410



Object Oriented MicroMagnetic Framework

Dependence of H_{ex} on the AFM correlation length λ

Dot size = 1200 nm

All the AFM cells with high K (100% pinning centers)

Different cell size: 10, 20, 100, 200, 300 nm







At low temperature

Spin correlation effect

Correlated AFM spins exert a stronger pinning action as $D/\lambda \rightarrow 1$

Conclusions

Re-entrant antiferromagnetism \Rightarrow Passage from the glassy to the AFM state

• **Re-entrant magnetic regime**: the magnetism of AFM interfacial spins is sustained by stable nanograins.

Exchange coupling mechanism

- Low temperature: collective freezing of the disordered AFM spins \Rightarrow high H_{ex}.
- High temperature: FM/AFM coupling governed by a fraction of interfacial AFM spins.
- **Spatial confinement** ⇒ spin correlation effect

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Thanks for attention